Record Nr. UNINA9910300430303321 Defects at Oxide Surfaces / / edited by Jacques Jupille, Geoff Thornton **Titolo** Cham:,: Springer International Publishing:,: Imprint: Springer,, Pubbl/distr/stampa 2015 **ISBN** 3-319-14367-0 Edizione [1st ed. 2015.] 1 online resource (472 p.) Descrizione fisica Collana Springer Series in Surface Sciences, , 0931-5195; ; 58 Disciplina 546.7212 Surfaces (Physics) Soggetti Interfaces (Physical sciences) Thin films Optical materials Electronic materials Materials—Surfaces Physical chemistry Surface and Interface Science, Thin Films Optical and Electronic Materials Surfaces and Interfaces, Thin Films Physical Chemistry

Lingua di pubblicazione Inglese

Formato Materiale a stampa

Livello bibliografico Monografia

Note generali Description based upon print version of record.

Nota di bibliografia Includes bibliographical references at the end of each chapters and

index.

Nota di contenuto From the Contents: Numerical simulations of defective structures --

Modeling oxygen vacancies -- Role of surface defects in photocatalysis -- Chemical activity of defects -- Nature of defects as determined by

scanning probe tip-surface interactions.

Sommario/riassunto This book presents the basics and characterization of defects at oxide

surfaces. It provides a state-of-the-art review of the field, containing information to the various types of surface defects, describes analytical methods to study defects, their chemical activity and the catalytic reactivity of oxides. Numerical simulations of defective structures complete the picture developed. Defects on planar surfaces form the focus of much of the book, although the investigation of powder

samples also form an important part. The experimental study of planar surfaces opens the possibility of applying the large armoury of techniques that have been developed over the last half-century to study surfaces in ultra-high vacuum. This enables the acquisition of atomic level data under well-controlled conditions, providing a stringent test of theoretical methods. The latter can then be more reliably applied to systems such as nanoparticles for which accurate methods of characterization of structure and electronic properties have yet to be developed. The book gives guidance to tailor oxide surfaces by controlling the nature and concentration of defects. The importance of defects in the physics and chemistry of metal oxide surfaces is presented in this book together with the prominent role of oxides in common life. The book contains contributions from leaders in the field. It serves as a reference for experts and beginners in the field.